Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/626,187	DAVIES, JOHN	
Examiner	Art Unit	
Teena Mitchell	3771	

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Class	Subclass	Date	Examiner
128	201.19 201.25 202.27 205.25	6/27/2007	TKM
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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